

Power Amplifier 55 - 70 GHz



MAAP-011215-DIE

Rev. V1

Features

- Saturated Output Power: 25 dBm
- Gain: 25 dBm
- OIP3: 32 dBm
- OIP5: 28 dBm
- Input Return Loss: 15 dBm
- Output Return Loss: 15 dBm
- Power Added Efficiency: 15%
- Variable gain with adjustable bias
- Integrated power detector
- Dimension: 2000 x 1700 x 50 μ m
- RoHS* Compliant
- Bare Die

Applications

- Point-to-Point Communications / Short Haul
- Radar Front Ends
- Test and Measurement
- Communication Transmitters

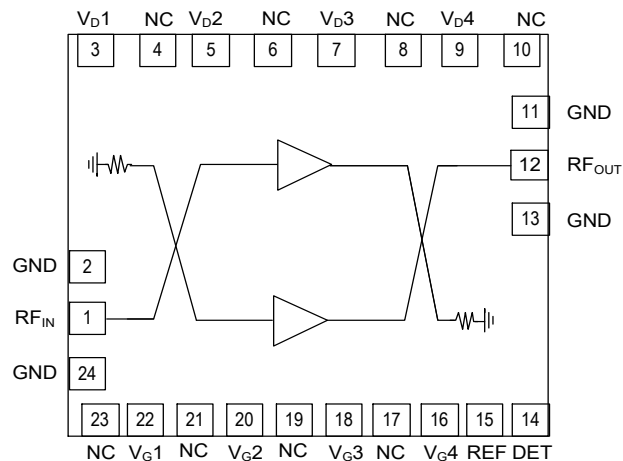
Description

The MAAP-011215-DIE is a balanced four stage GaAs pHEMT MMIC power amplifier achieving an output power of 25 dBm in the range 55 to 70 GHz.

Ordering Information

Part Number	Package
MAAP-011215-DIE	Vacuum Release Gel Pack

Functional Schematic



Pad Configuration¹

Pad #	Function
1	RF Input
2,11,13,24	GND
3	Drain Voltage 1
4,6,8,10,17,19,21,23	NC
5	Drain Voltage 2
7	Drain Voltage 3
9	Drain Voltage 4
12	RF Output
14	Detector Output
15	Detector Reference
16	Gate Voltage 4
18	Gate Voltage 3
20	Gate Voltage 2
22	Gate Voltage 1

1. The exposed metal on the MMIC bottom must be connected to RF, DC and thermal ground.

* Restrictions on Hazardous Substances, compliant to current RoHS EU directive.

Electrical Specifications²: Frequency = 55 - 70 GHz, T_A = +25°C, V_D = 4 V, I_{DQ} = 400 mA

Parameter	Test Conditions	Units	Min.	Typ.	Max.
Gain	55 GHz	dB	18	25	—
	60 GHz		18	25	
	65 GHz		17	24	
	70 GHz		17	24	
Input Return Loss	—	dB	—	15	—
Output Return Loss	—	dB	—	15	—
Saturated Output Power	—	dBm	—	25	—
OIP3	—	dBm	—	32	—
Drain Bias Voltage	—	V	—	4	—
Power Added Efficiency	—	%	—	15	—

2. Quiescent DC Bias: I_{D1} = 40 mA, I_{D2} = 80 mA, I_{D3} = 120 mA, I_{D4} = 160 mA. Total DC power = 1.6 W.

Absolute Maximum Ratings^{3,4,5}

Parameter	Absolute Maximum
Drain Voltage	4.3 V
Drain Current	635 mA
Gate Bias Voltage (V _{G1,2,3})	-1.5 V < V _G < +0.3 V
Input Power	20 dBm
Storage Temperature	-55°C to +150°C
Operating Temperature	-40°C to +85°C
Junction Temperature ^{5,6}	+150°C

- Exceeding any one or combination of these limits may cause permanent damage to this device.
- MACOM does not recommend sustained operation near these survivability limits.
- Operating at nominal conditions with T_J ≤ +150°C will ensure MTTF > 1 x 10⁶ hours.
- Typical thermal resistance (θ_{jc}) = 25.6°C/W.
Junction Temperature (T_J) = Back Plate Temperature (T_{bp}) + θ_{jc} * (V * I)
 - For T_{bp} = +25°C,
T_J = 66°C @ 4 V, 400 mA
 - For T_{bp} = +85°C,
T_J = 129°C @ 4 V, 400 mA

Handling Procedures

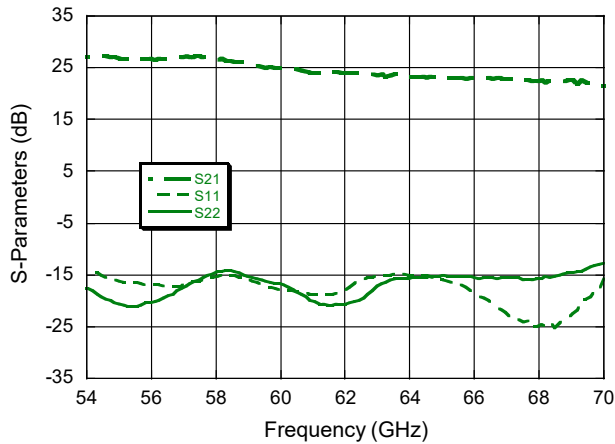
Please observe the following precautions to avoid damage:

Static Sensitivity

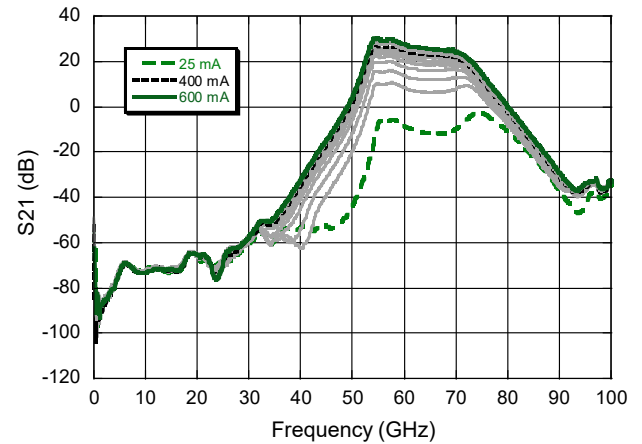
These electronic devices are sensitive to electrostatic discharge (ESD) and can be damaged by static electricity. Proper ESD control techniques should be used when handling these Class 1A (HBM) devices.

Typical S-Parameter Performance Curves @ +25°C, $V_D = 4$ V,
(25, 50, 100, 150, 200, 250, 300, 350, 400, 450, 500, 550, 600 mA)

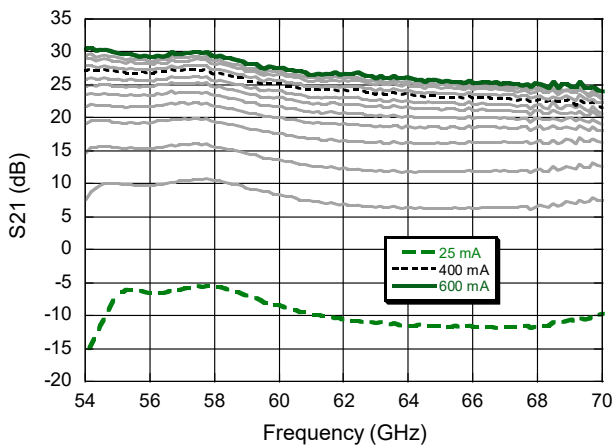
S-parameter @ $I_{DSQ} = 400$ mA



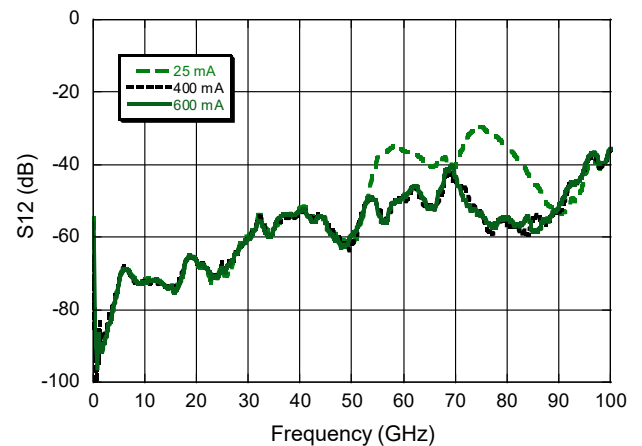
Gain



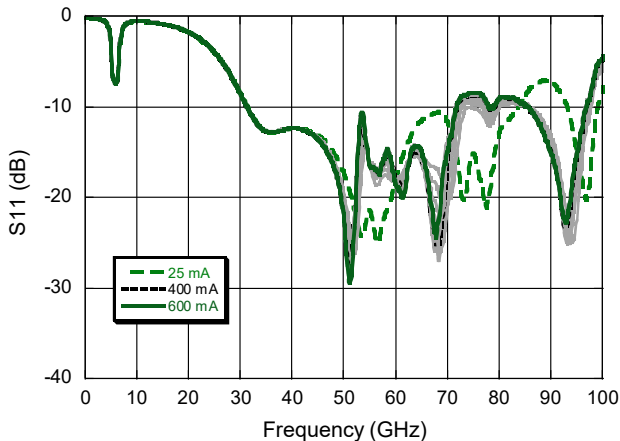
Gain 54 - 70 GHz



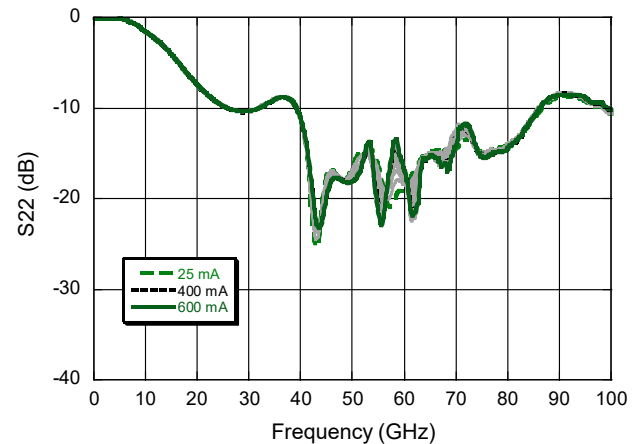
Reverse Isolation



Input Return Loss

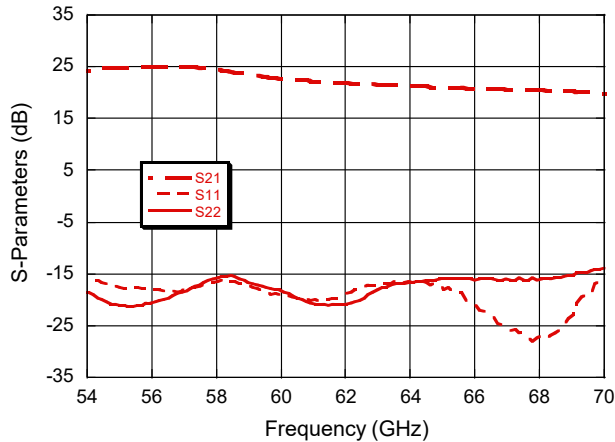


Output Return Loss

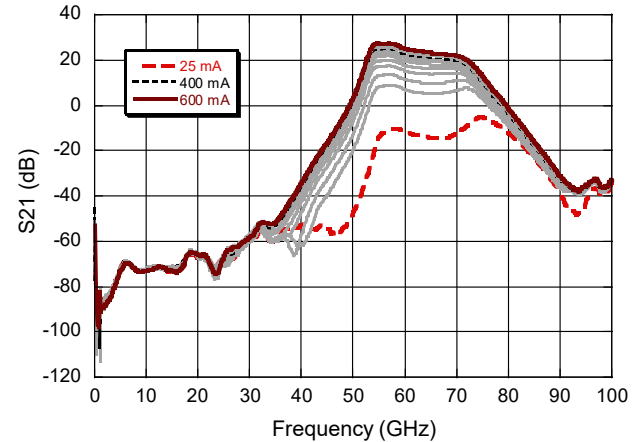


Typical S-Parameter Performance Curves @ +85°C, $V_D = 4\text{ V}$ (25, 50, 100, 150, 200, 250, 300, 350, 400, 450, 500, 550, 600 mA)

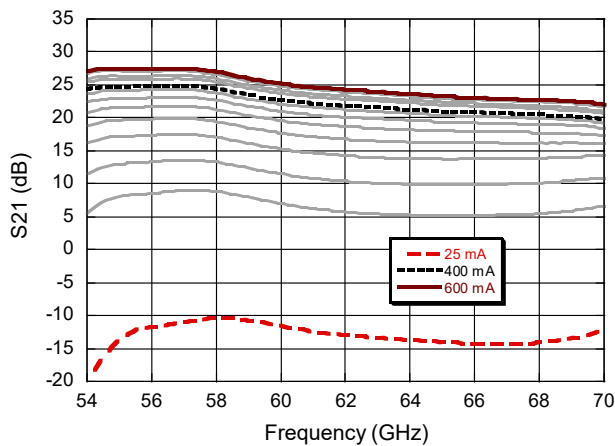
S-parameter @ $I_{DSQ} = 400\text{ mA}$



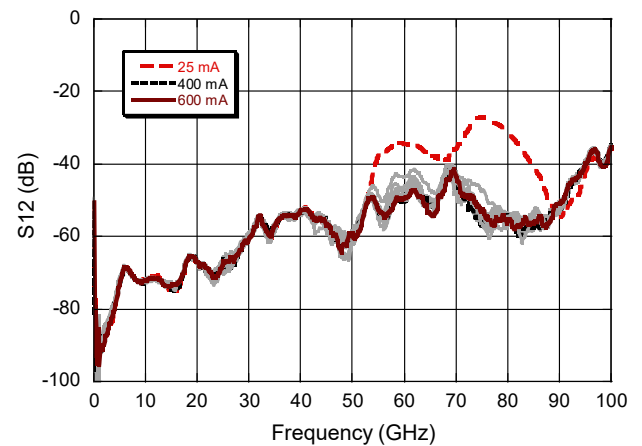
Gain



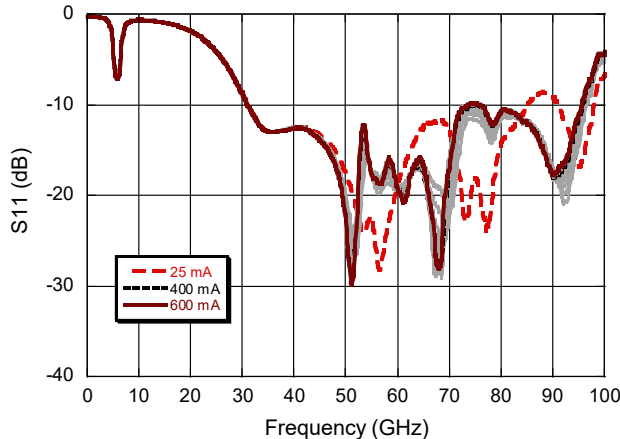
Gain 54 - 70 GHz



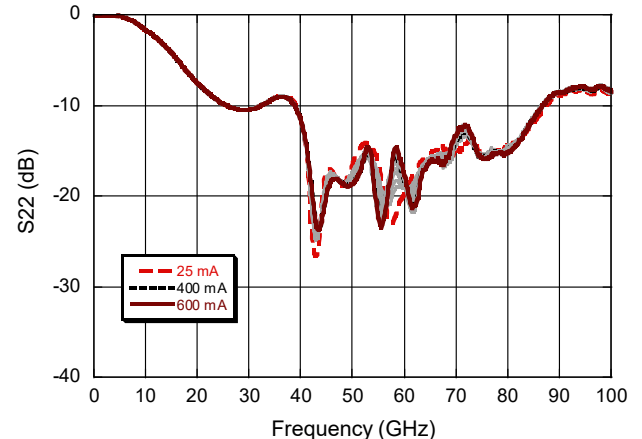
Reverse Isolation



Input Return Loss

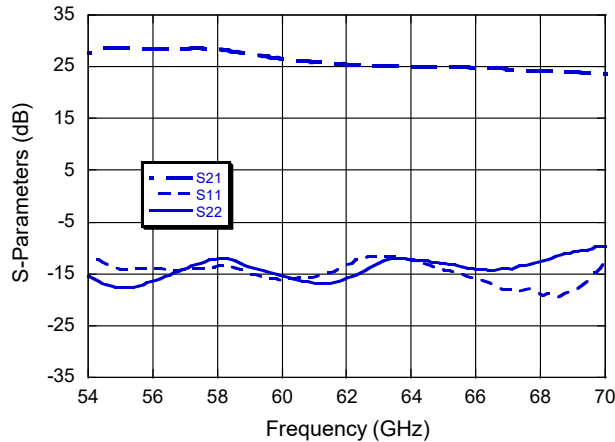


Output Return Loss

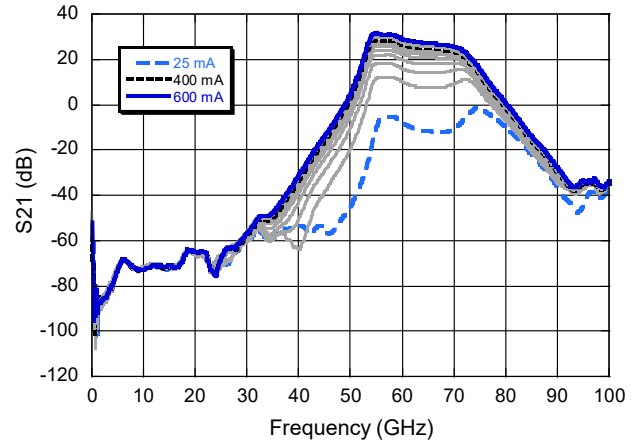


Typical S-Parameter Performance Curves @ -40°C, $V_D = 4$ V
(25, 50, 100, 150, 200, 250, 300, 350, 400, 450, 500, 550, 600 mA)

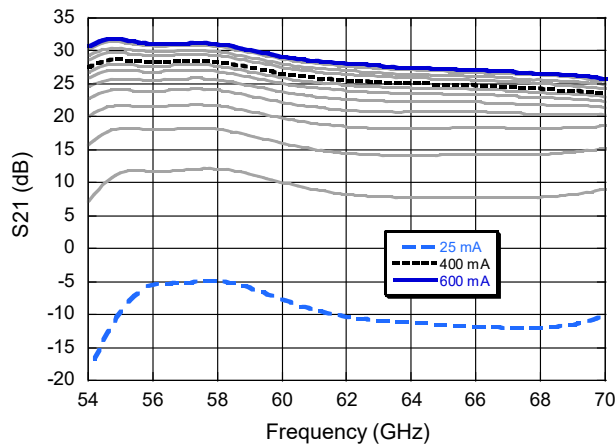
S-parameter @ $I_{DSQ} = 400$ mA



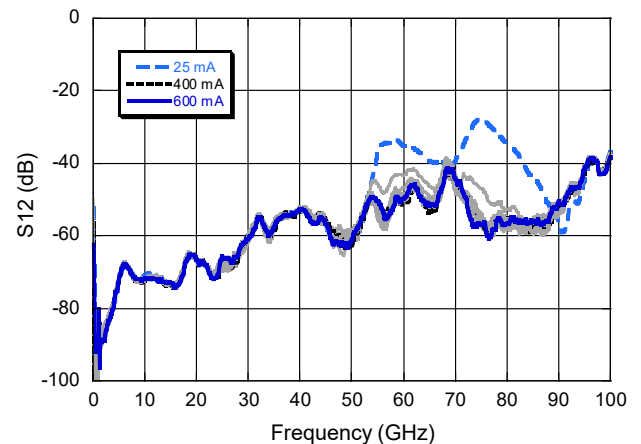
Gain



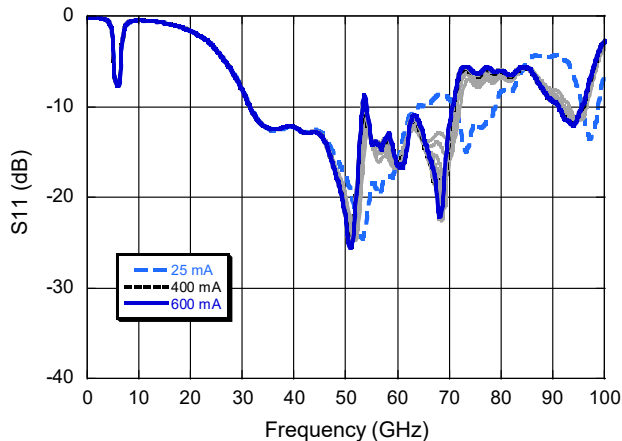
Gain 54 - 70 GHz



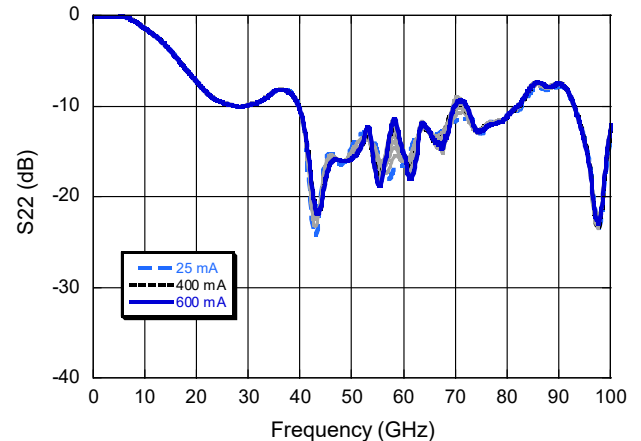
Reverse Isolation



Input Return Loss

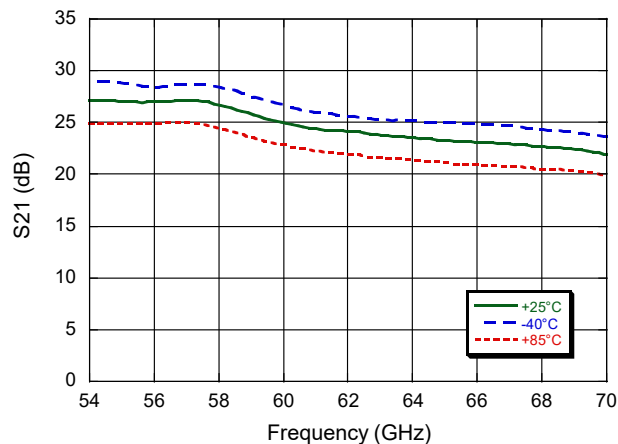


Output Return Loss

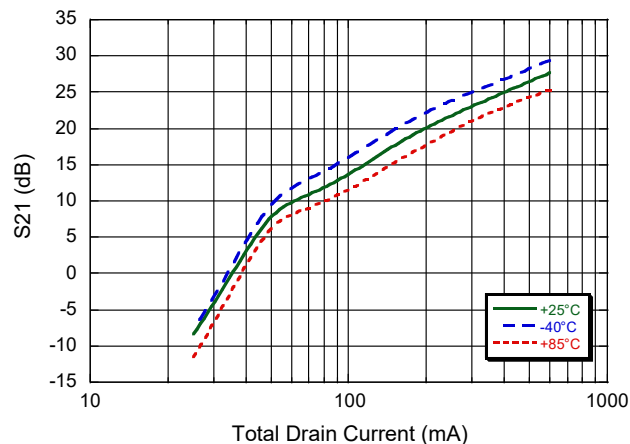


Typical S-Parameter Performance Curves over Temperature

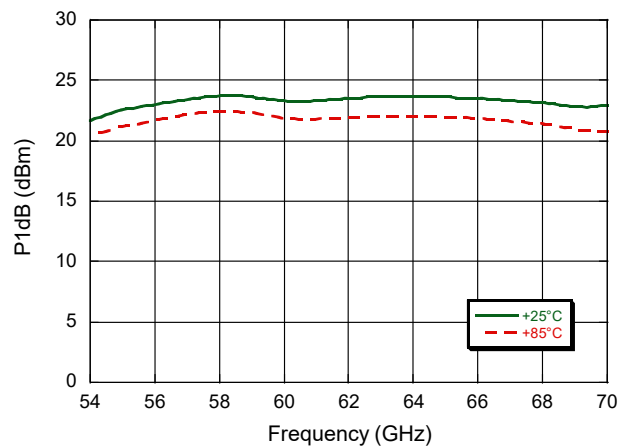
Gain @ 400 mA



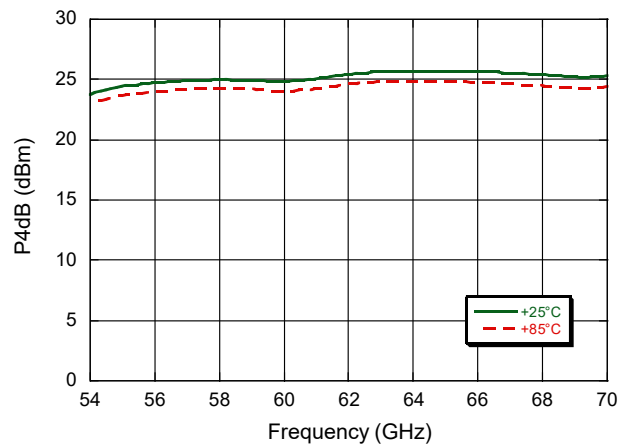
Gain @ 60 GHz vs. Drain Current



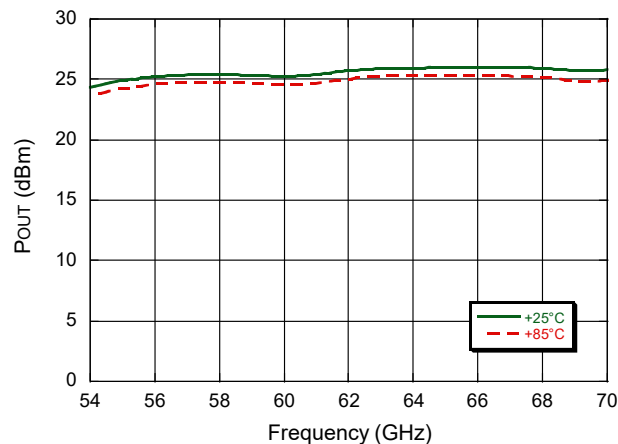
P1dB @ $I_{DSQ} = 400$ mA



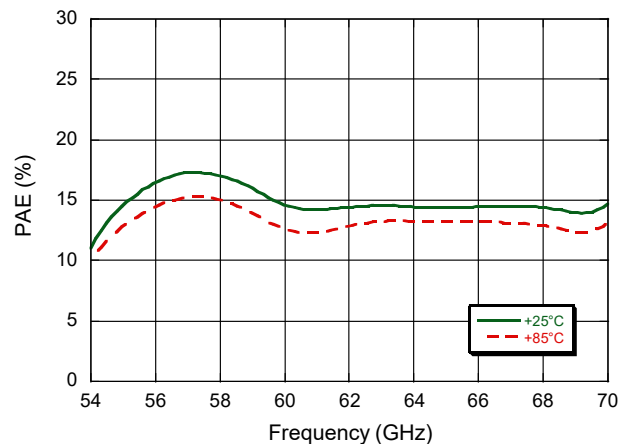
P4dB @ $I_{DSQ} = 400$ mA



P_{OUT} @ $P_{IN} = 12$ dBm and $I_{DSQ} = 400$ mA

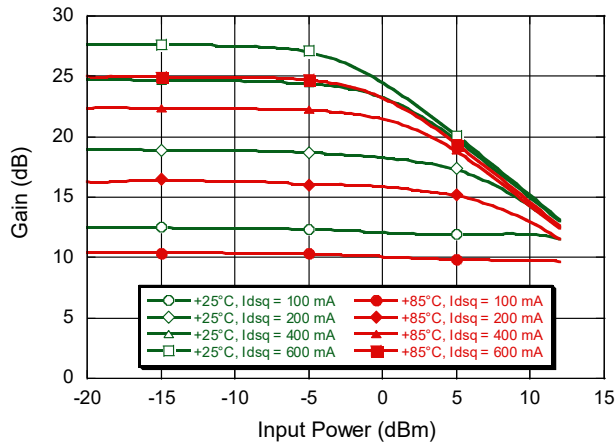


PAE @ $P_{IN} = 12$ dBm and $I_{DSQ} = 400$ mA

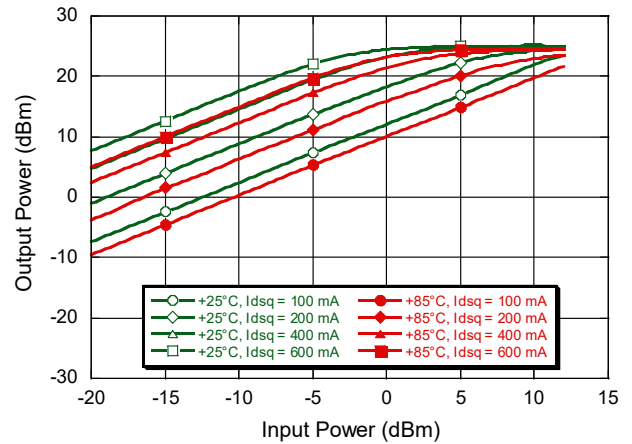


Typical Power Performance Curves @ +25°C and +85°C

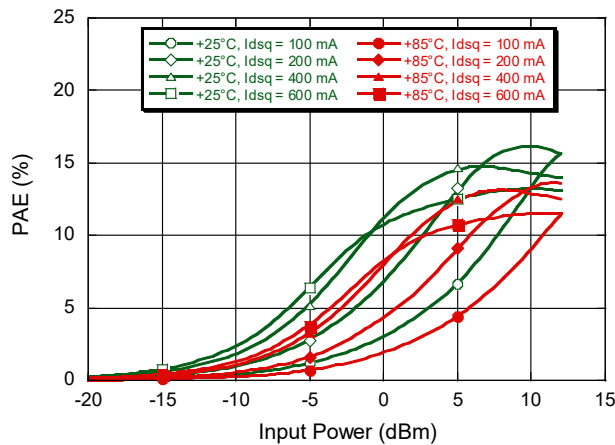
Scalar Gain @ 60 GHz vs. P_{IN} and I_{DSQ}



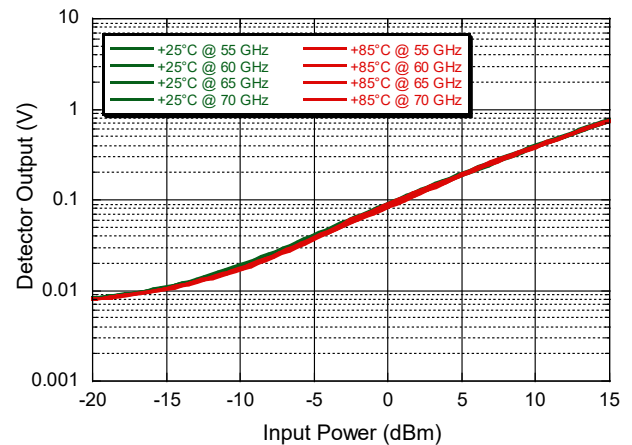
Output Power @ 60 GHz vs. P_{IN} and I_{DSQ}



PAE @ 60 GHz vs. P_{IN} and I_{DSQ}

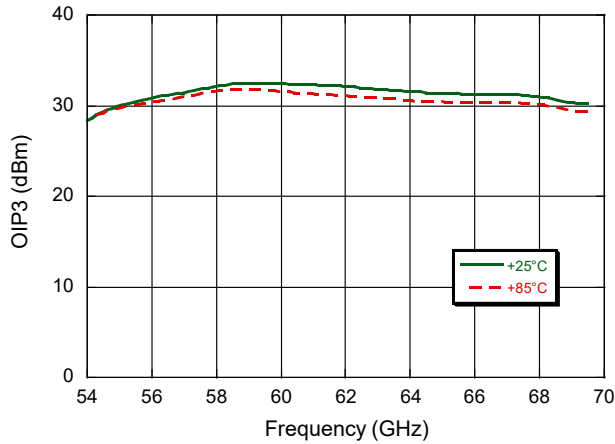


Power Detector Output @ 55, 60, 65 and 70 GHz

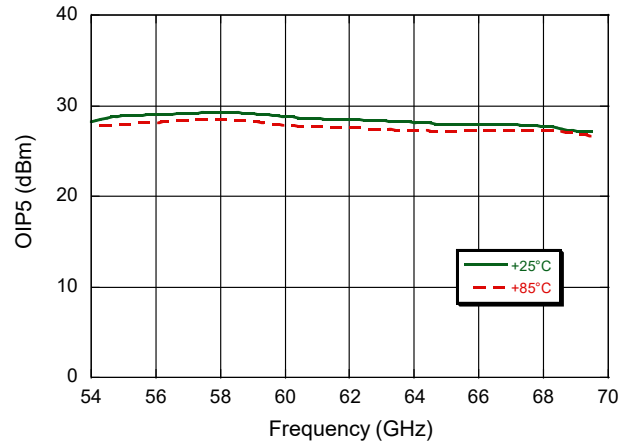


Typical Linearity Performance Curves @ 400 mA, $V_D = 4$ V, +25°C and +85°C

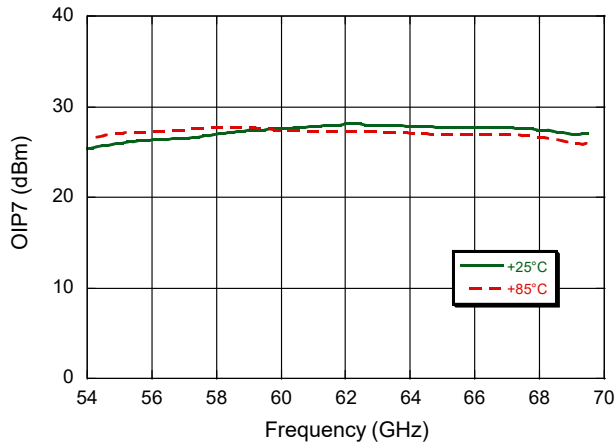
OIP3 and $P_{IN} = -10$ dBm per Tone



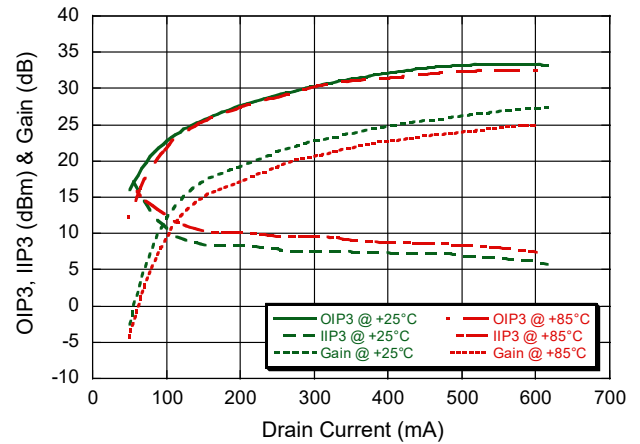
OIP5 and $P_{IN} = -10$ dBm per Tone



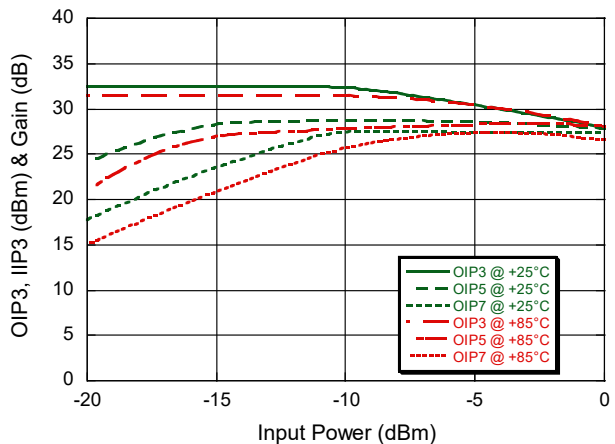
OIP7 and $P_{IN} = -5$ dBm per Tone



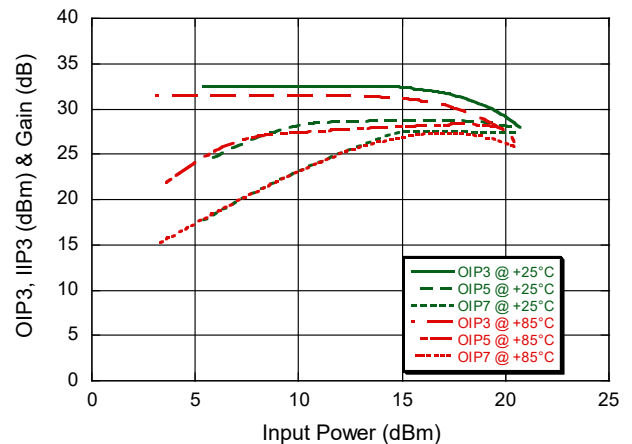
Gain, OIP3 and IIP3 vs. Drain Current at 60 GHz



OIP3, OIP5 and OIP7 vs. P_{IN}



OIP3, OIP5 and OIP7 vs. P_{OUT}



Calibration Plane

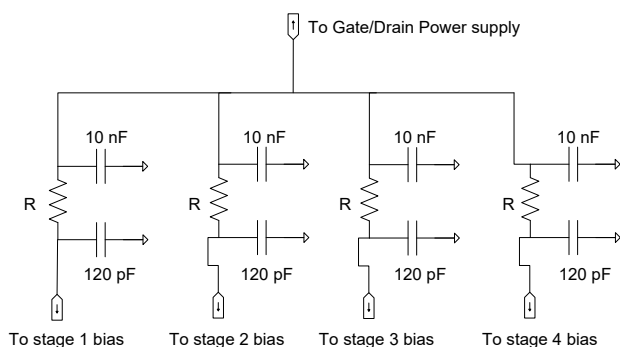
All data was measured on die with 200 μm pitch probes. The calibration plane is at the middle of the through, 178.5 μm from the middle of the RF pad.

App Note [1] Biasing -

All gates should be pinched-off ($V_G < -1\text{ V}$) before applying drain voltage ($V_D = 4\text{ V}$). Then the gate voltages can be increased until the desired quiescent drain current is reached in each stage. The recommended quiescent bias is $V_D = 4\text{ V}$, $I_{D1} = 40\text{ mA}$, $I_{D2} = 80\text{ mA}$, $I_{D3} = 120\text{ mA}$ and $I_{D4} = 160\text{ mA}$. The performance in this datasheet has been measured with fixed gate voltage and no drain current regulation under large signal operation. It is also possible to regulate the drain current dynamically, to limit the DC power dissipation under RF drive. To turn off the device, the turn on bias sequence should be followed in reverse.

App Note [2] Bias Arrangement -

Each DC pin ($V_{D1,2,3,4}$ and $V_{G1,2,3,4}$) needs to have bypass capacitance (120 pF and 10 nF) mounted as close to the MMIC as possible.

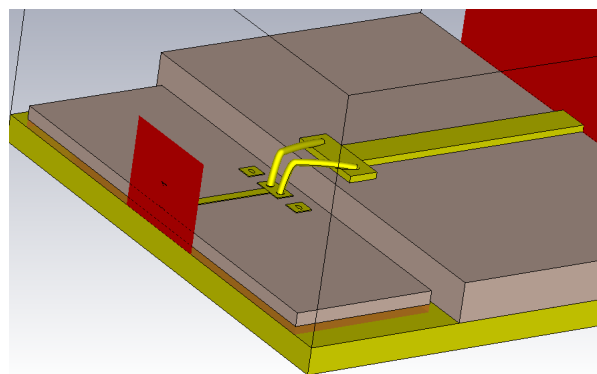


App Note [3] Common Gates and Drains -

When biasing the device with only a single gate or drain source additional isolation is required between each stage. On the gate side a 10 Ω resistor should be placed in series and tied together in a star to a common supply. The drain side resistance should be reduced to less than 5 Ω to minimize any voltage drop across the resistor. Suitable bias pass capacitance should still be applied to each stage as per App Note [2].

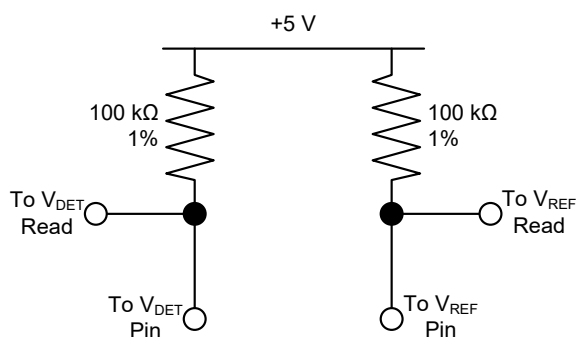
App Note [4] Wire Bonding -

The loop height of the RF bonds should be minimized. Where the die is mounted above the PCB, it is recommended to use Reverse Ball-Stitch-on-Ball bonds (BSOB). If the die is mounted inside a cavity on the board, forward loop bonding may result in a lower loop height. V-shape RF bond with two wires (diameter = 25 μm) is recommended for optimum RF performance. RF bond wire length to be minimized to reduce the inductance effect. Simulations suggest no more than 300 μm . Substrate RF pad can be optimized to improve the microstrip to MMIC bond transition as shown in the example below.



App Note [5] Detector biasing schematic -

As shown in the schematic below, the power detector is implemented by providing 5 V bias and measuring the difference in output voltage. This measure can be achieved by mean of either standard op-amp in a differential mode configuration or analog-to-digital converters.

**App Note [6] Handling the Die -**

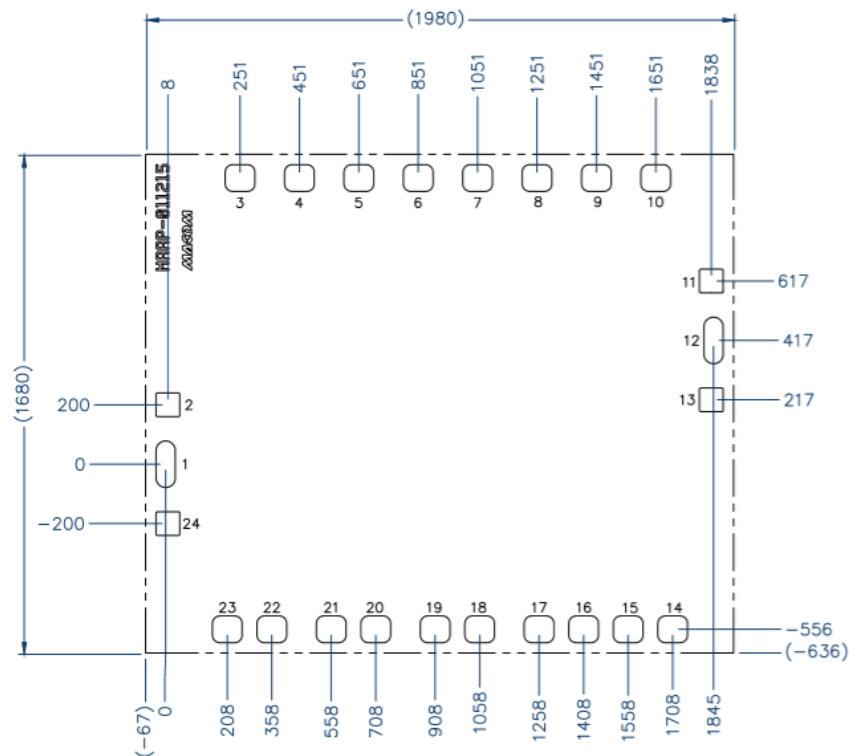
This MMIC has fragile exposed airbridges on its surface and must be handled on the edges only using a vacuum collet or suitable tweezers. Do not touch the surface of the chip with a vacuum collet, tweezers, or fingers.

App Note [7] Die Attach -

For mounting the die either an electrically conductive epoxy, or an AuSn eutectic preform can be used.

If using eutectic, an 80% Au / 20% Sn preform is recommended. If using epoxy, a high thermal conductivity epoxy is required and a silver sintering type epoxy is recommended.

Die Outline



Unless otherwise specified, all dimensions shown are μm , with a tolerance of $\pm 5 \mu\text{m}$.
Die thickness is $50 \mu\text{m} \pm 10 \mu\text{m}$.
Bondpad backside metallization: Gold
Die size reflects final dimensions.

Bond Pad Dimensions (μm)

Pad #	X	Y	Pin Label
1	65	157	RF Input
2,11,13,24	80	80	GND
3	100	90	Drain Voltage 1
4,6,8,10,17,19,21,23	92	142	NC
5	100	90	Drain Voltage 2
7	100	90	Drain Voltage 3
9	100	90	Drain Voltage 4
12	65	157	RF Output
14	100	90	Detector Output
15	100	90	Detector Reference
16	100	90	Gate Voltage 4
18	100	90	Gate Voltage 3
20	100	90	Gate Voltage 2
22	100	90	Gate Voltage 1

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